



JT 5510 / JT 5550

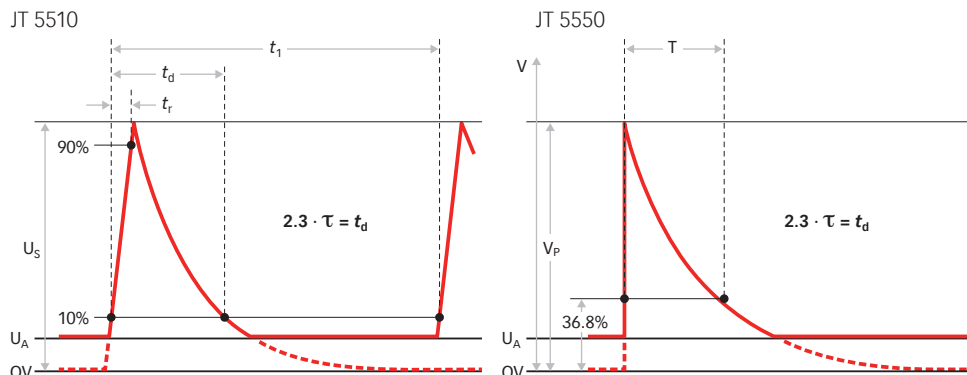
JT 5510 TRANSIENT GENERATOR

JT 5550 LOAD DUMP GENERATOR



The JASO D001-94 from the Japanese Automotive Standards Organization departs from the traditional ISO/SAE pulses in significant ways. These pulses have a 1 μ s rise time, use special output impedances, methods of measuring pulse width, and pulse coupling. The JASO D001-94 forms the basis of other Japanese standards. This is one of a series of Gemini JASO based modules that was developed for usage with a NSG 5500 capacitive discharge immunity simulation system.

- Plug-in modules for JASO D001-94
- For many classic Japanese immunity tests
- Cost-effective addition to the NSG 5500 automotive transient generator



These classic pulses are sometimes used as the base for other standards, Nissan for example. Therefore, other pulses are also covered by this module.

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Technical information JT 5510

Standard	Version	Year	Pulse name	Polarity	Amplitude		tr [μs]	td [μs]	Pulse width		Repetition rate	
					Min [V]	Max [V]			t [μs]	Ri [Ω]	Min [s]	Max [s]
JASO	D001-94	1994	Pulse A-2	positive	20	110	<1	5.75	2.5	0.4	1	120
JASO	D001-94	1994	Pulse D-2	positive	20	170	<1	5.75	2.5	0.9	1	120
JASO	D001-94	1994	Pulse B-1	negative	20	80	<1	138,000	60,000	8	6	120
JASO	D001-94	1994	Pulse B-2	negative	20	260	<1	4,600	2,000	80	6	120
JASO	D001-94	1994	Pulse E	negative	20	320	<1	60,000	26,000	210	30	120
Nissan	28400 NDS3	1997	Pulse B-1	positive	20	80	<1	46,000	*	*	3	120
Nissan	28402 NDS3	1997	Pulse B-2	negative	20	300	<1	7,600	*	*	3	120

Technical information JT 5550

Standard	Version	Year	Pulse name	Polarity	Amplitude		tr [μs]	td [μs]	Pulse width		Repetition rate	
					Min [V]	Max [V]			t [μs]	Ri [Ω]	Min [s]	Max [s]
JASO	D001-94	1994	Pulse A1	positive	50	110	<1	460	200	0.8	30	60
JASO	D001-94	1994	Pulse D1	positive	50	120	<1	920	400	1.5	30	60

* Pulse width values typical - defined by pulse generation circuit, not by pulse characteristics

Note: The pulse shaping networks are designed internally with a 1 μs rise time. However, due to system capacitance of the 100 A coupler, typical rise times measured at the output of the system can be 3 μs or more.

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